

P1M120HB007P66

Full Silicon Carbide Half-Bridge Power Module
N-CHANNEL ENHANCEMENT MODE

Features

- Low On-Resistance and High Current Density
- Low Capacitance for High Frequency Operation
- Ease of Temperature Sensing by Embedded NTC
- Positive Temperature Coefficient Device
- RoHS Compliant and Halogen Free
- AlN-AMB Insulator

Benefits

- Higher System Efficiency
- Increase Parallel Device Convenience
- Temperature Independent Switching Behavior
- Allow High Frequency Operation
- Realize Compact and Lightweight Systems

Applications

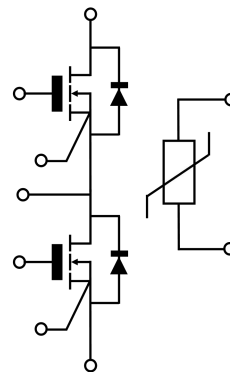
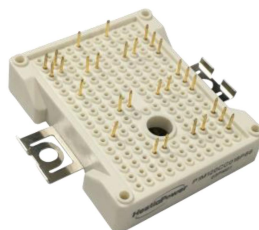
- Induction Heating
- DC/DC Converter
- Motion/Servo Control
- UPS and SMPS
- Solar/Wind Renewable Energy

Product Summary

V_{DS}	1200V
$I_D(@25^\circ\text{C})$	325A
$R_{DS(on)}$	7m Ω



Product Overview



Description

P1M120HB007P66 1200V, 7m Ω SiC power module is a full SiC half-bridge power module that implementing N-channel e-mode SiC MOSFETs. Exploiting the outstanding wide bandgap material properties, this module shows better current density and switching behavior (tail-current-free & temperature independent dynamic performance) compared to conventional Si IGBT modules.

Absolute Maximum Ratings ($T_c = 25^\circ\text{C}$ unless otherwise specified)

SiC MOSFET

Parameter	Symbol	Test Conditions	Value	Unit
Drain – Source Voltage	$V_{DS, max}$	$V_{GS}=0V, I_D=500\mu A$	1200	V
Continuous Drain Current	I_D	$V_{GS}=20V, T_c=25^\circ\text{C}$	325*	A
		$V_{GS}=20V, T_c=75^\circ\text{C}$	270*	
Pulse Drain Current	$I_{D, pulse}$	$t_{PW}=200\mu s$	680*	
Power Dissipation	P_D	$T_c=25^\circ\text{C}$	1764*	W
Recommend Gate Source Voltage	$V_{GS, op}$	Static, recommended DC operating values	-5 to 20	V
Maximum Gate Source Voltage	$V_{GS, max}$	Transient operating limit (AC f > 1Hz, duty cycle < 1%)	-10 to 25	

SiC MOSFET Electrical Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=500\mu A$	1200			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=10V, I_D=180mA$		3.0		V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=1200V, V_{GS}=0V$		<5	450	μA
		$V_{DS}=1200V, V_{GS}=0V$ $T_j=175^\circ\text{C}$		100	1500	
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=20V, V_{DS}=0V$			1	μA
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS}=20V, I_D=180A$		7	9	m Ω
		$V_{GS}=20V, I_D=180A, T_j=175^\circ\text{C}$		12		
Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=800V$ $f=1MHz, V_{AC}=25mV$		20*		nF
Output Capacitance	C_{oss}			1.0*		
Reverse Transfer Capacitance	C_{rss}			0.17*		
Effective Output Capacitance, Energy Related	$C_{o(er)}$		$V_{GS}=0V,$ $V_{DS}=0$ to 800V		1.35*	
Effective Output Capacitance, Time Related	$C_{o(tr)}$	$I_D=const., V_{GS}=0V,$ $V_{DS}=0$ to 800V		1.90*		
Turn On Delay Time	$t_{d(on)}$	$V_{DS}=800V, V_{GS}=-4/20V,$ $I_D=180A, R_L=4.4\Omega,$ $R_{G(ext)}=0.3\Omega$		40*		ns
Rise Time	t_r			39*		
Turn Off Delay Time	$t_{d(off)}$			35*		
Fall Time	t_f			24*		
C_{oss} Stored Energy	E_{oss}	$V_{GS}=0V, V_{DS}=800V$ $f=1MHz, V_{AC}=25mV$		423*		μJ
Turn-on Switching Energy	E_{on}	$V_{DS}=800V, V_{GS}=0/20V,$ $I_D=180A,$		4293*		μJ
Turn-off Switching Energy	E_{off}	$R_{G(ext)}=0.3\Omega$		918*		
Internal Gate Resistance	$R_{G(int.)}$	$f=1MHz, V_{AC}=25mV$		0.13*		Ω
Gate to Source Charge	Q_{GS}	$V_{DS}=800V,$ $V_{GS}=-5/+20V,$ $I_D=180A$		261*		nC
Gate to Drain Charge	Q_{GD}			576*		
Total Gate Charge	Q_G			1161*		
Gate plateau voltage	V_{pl}			7*		

Built-in SiC Diode Electrical Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Typ.	Unit
Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_{SD}=150A$	4.7	V
Continuous Diode Forward Current	I_S	$V_{GS}=0V, T_c=25^\circ\text{C}$	300*	A
Reverse Recovery Time	t_{rr}	$V_{GS}=0V,$	513*	ns
Reverse Recovery Charge	Q_{rr}	$I_{SD}=180A, V_{DS}=400V,$	981*	nC
Peak Reverse Recovery Current	I_{rrm}	$di/dt=300A/\mu s$	31.5*	A

* By estimation.

Thermal Characteristics (T_c = 25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Value	Unit
Max Junction Temperature	T _{Jmax}		175	°C
Operating Temperature	T _{Jop}		-55~175	
Storage Temperature	T _{stg}		-55~175	
Thermal Resistance, Junction to Case	R _{th(j-c)}	JESD51-14	0.085	°C/W

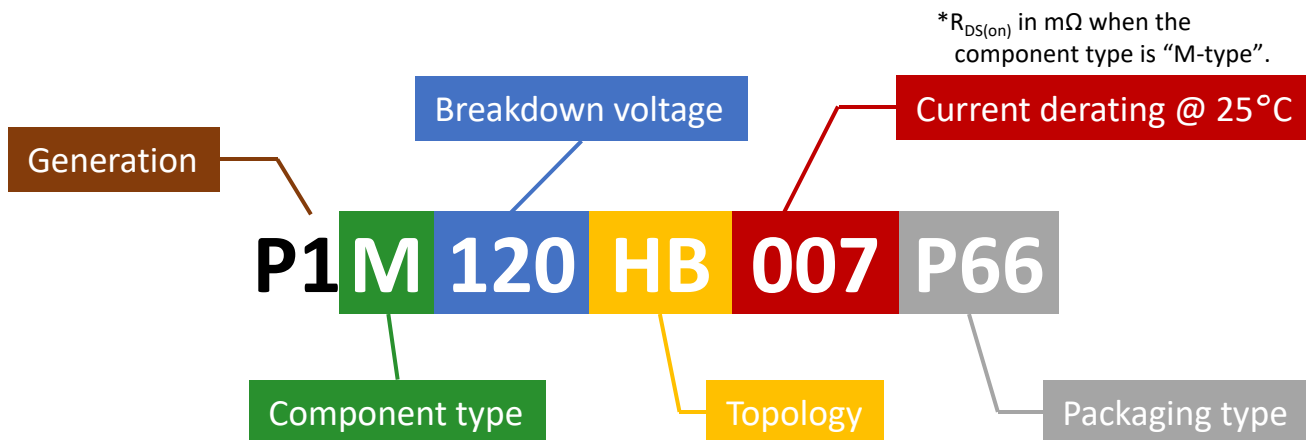
NTC Characteristics

Parameter	Symbol	Test Conditions	Value	Unit
Resistance	R ₂₅	T _c = 25°C	5	kΩ
B-value	B _{25_150}	$R_2 = R_{25} \exp [B_{25_150}(1/T_2 - 1/(298.15K))]$	3380	K

Mechanical Characteristics

Parameter	Symbol	Test Conditions	Value	Unit
Isolation Breakdown Voltage	V _{iso}	AC, 50Hz (R.M.S), t=1minute	3000	V
Comparative Tracking Index	CTI		>200	-
Mounting Torque	τ _{tc}	Recommended (M6 screw)	3~5	Nm
Weight	W		25	g

Naming Rule



Typical Device Performance

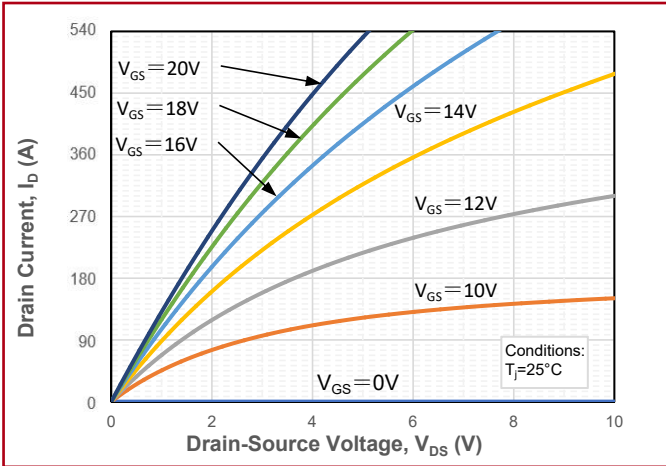


Fig.1 Forward Output Characteristics at $T_j = 25^\circ\text{C}$

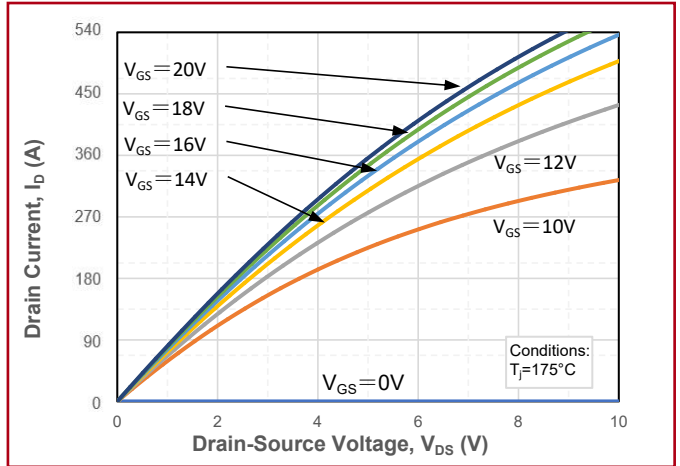


Fig.2 Forward Output Characteristics at $T_j = 175^\circ\text{C}$

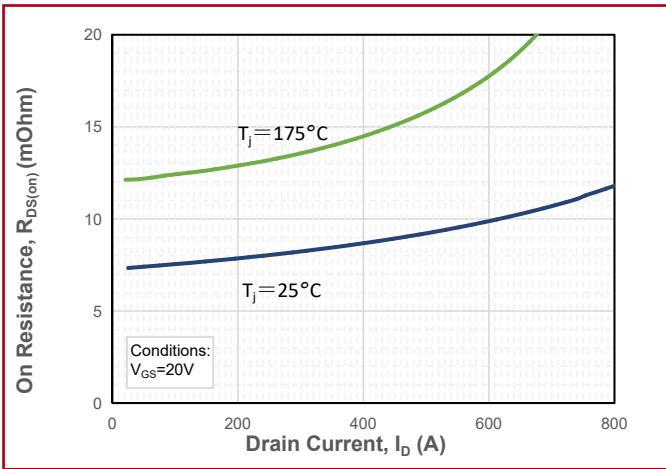


Fig.3 On-Resistance vs. Drain Current for Various T_j

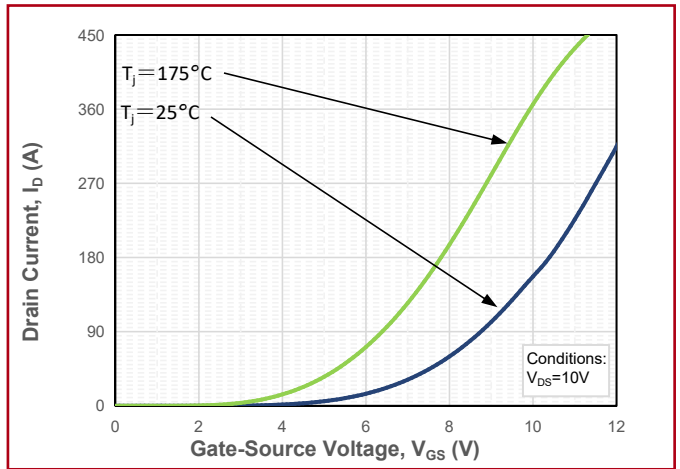


Fig.4 Transfer Characteristics for Various T_j

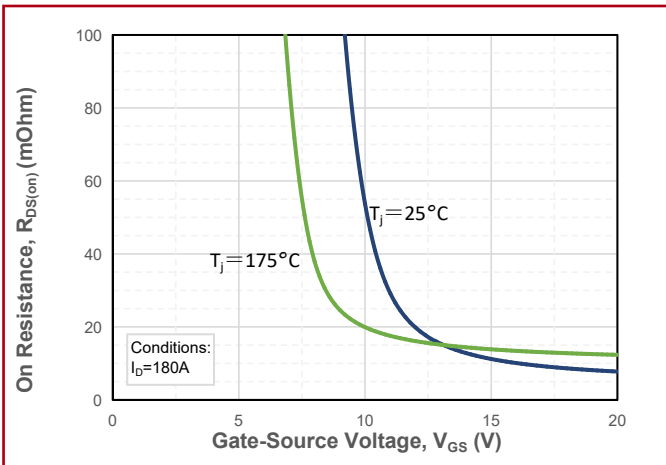


Fig.5 On-Resistance vs. Gate Voltage for Various T_j

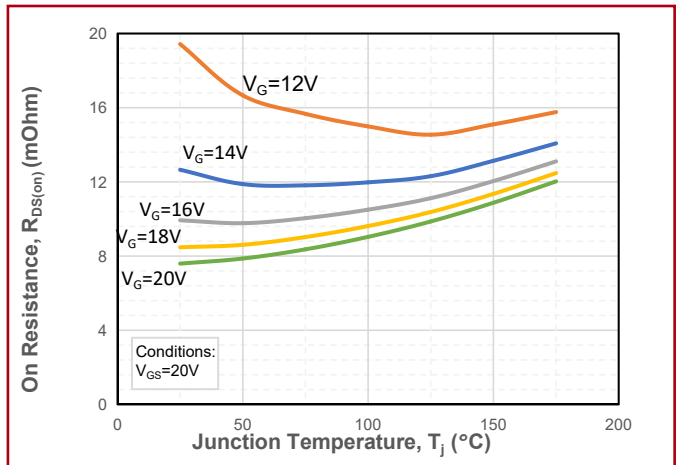


Fig.6 On-Resistance vs. Temperature for Various Gate Voltage

Typical Device Performance

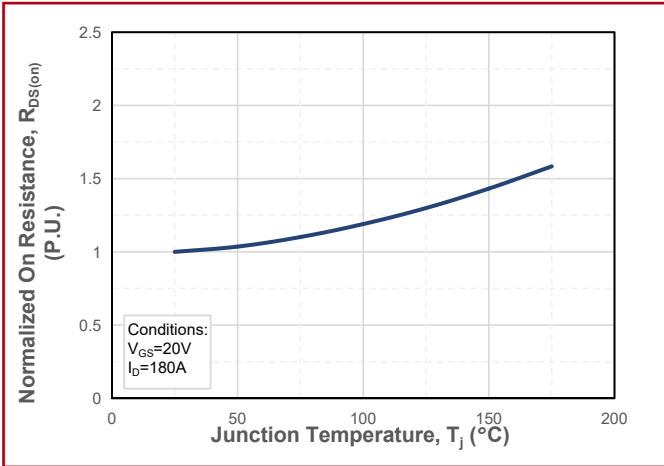


Fig.7 Normalized On-Resistance vs. Temperature

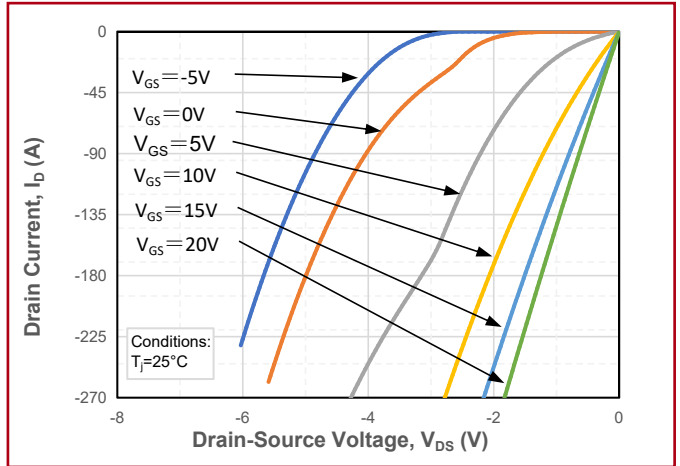


Fig.8 Reverse Output Characteristics at $T_j = 25^\circ\text{C}$

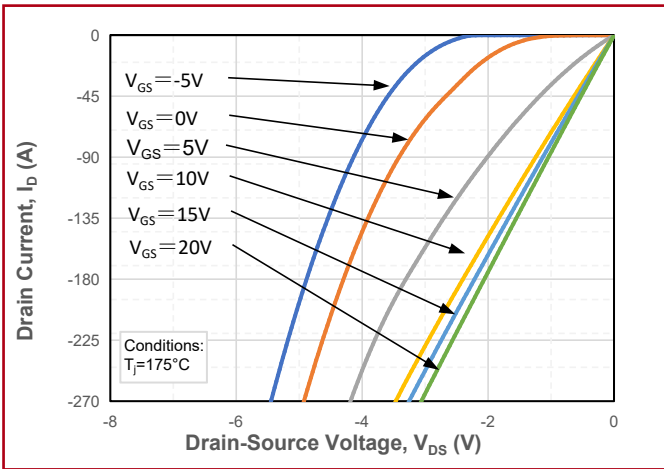


Fig.9 Reverse Output Characteristics at $T_j = 175^\circ\text{C}$

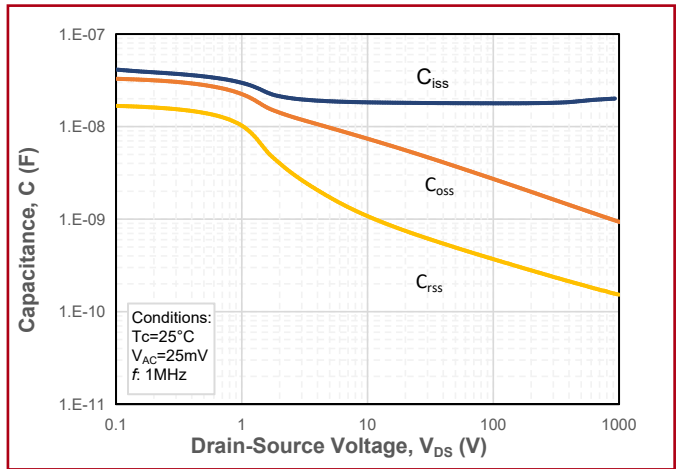


Fig.10 Capacitances vs. Drain to Source Voltage

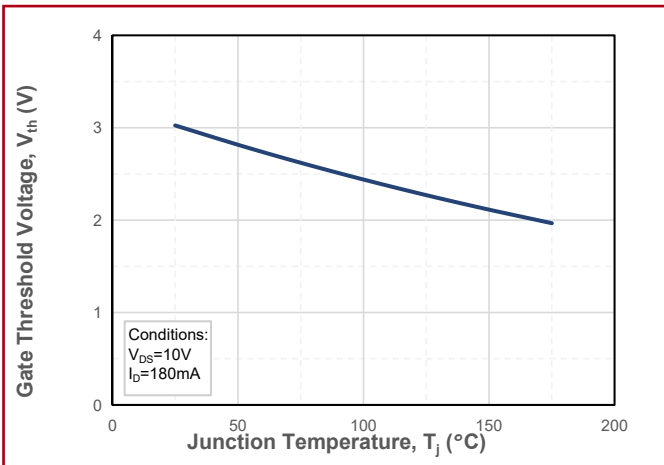


Fig.11 Threshold Voltage vs. Temperature

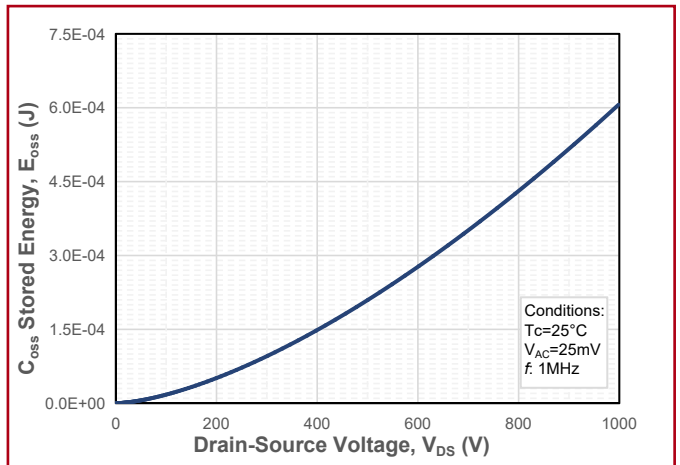


Fig.12 Output Capacitor Stored Energy

Typical Device Performance

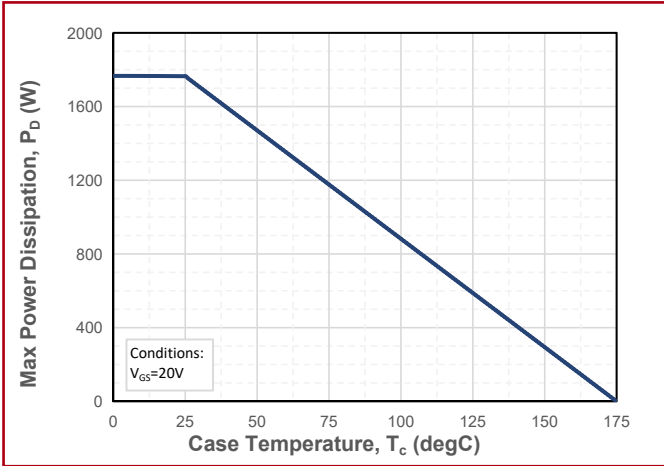


Fig.13 Maximum Power Dissipation Derating vs. Case Temperature

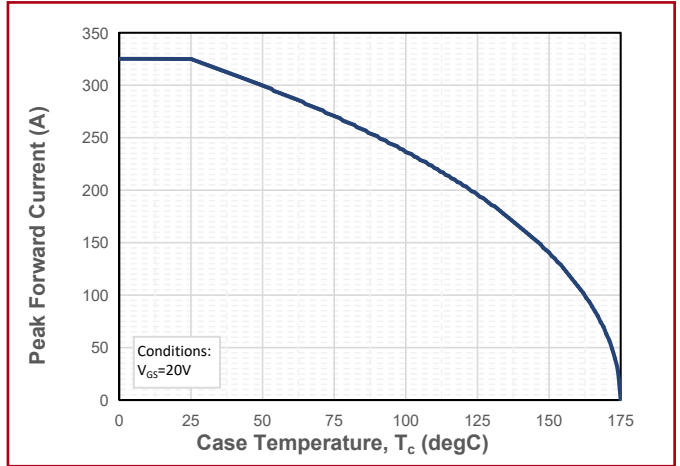


Fig.14 Drain Current Derating vs. Case Temperature

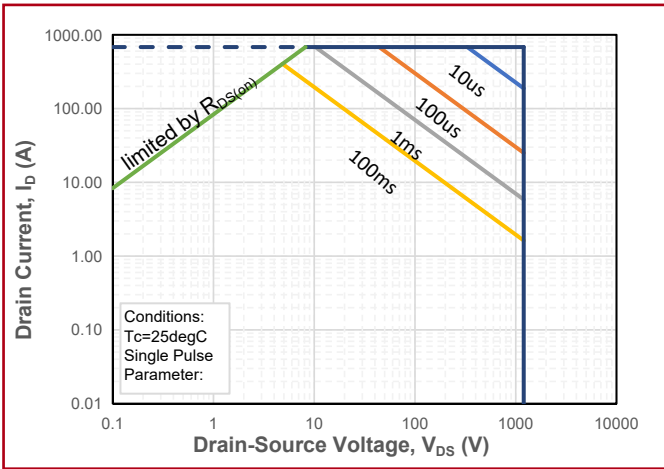


Fig.15 Safe Operating Area

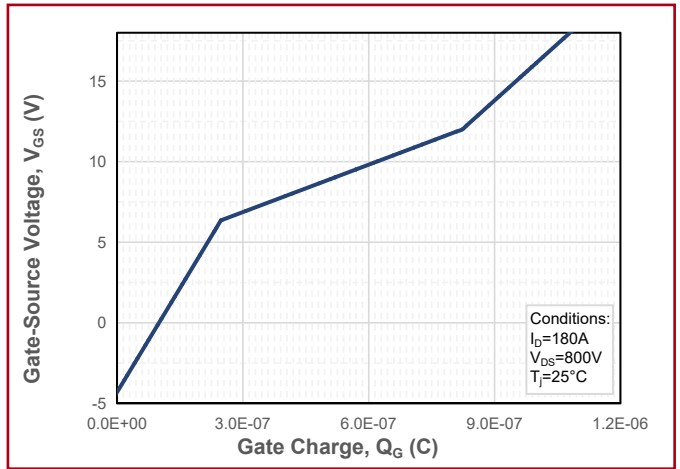


Fig.16 Gate Charge Characteristics

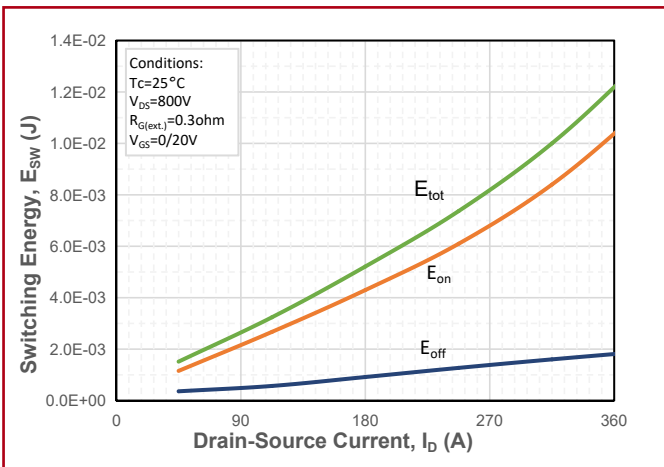


Fig.17 Clamped Inductive Switching Energy vs. Drain Current

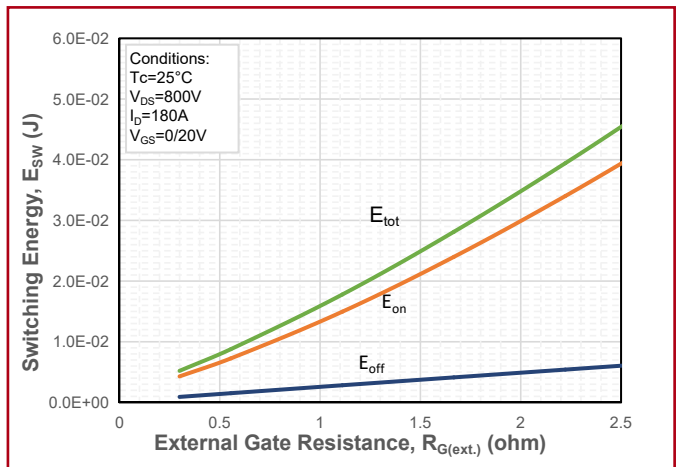


Fig.18 Clamped Inductive Switching Energy vs. External Gate Resistor ($R_{G(ext.)}$)

Typical Device Performance

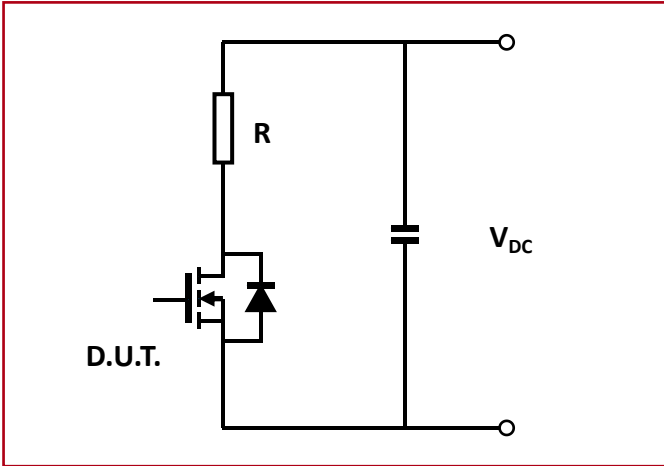


Fig.19 Schematic of Resistive Switching

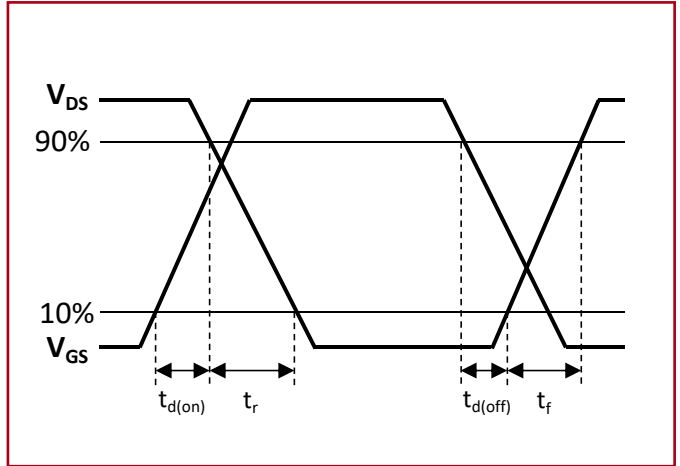


Fig.20 Switching Times Definition

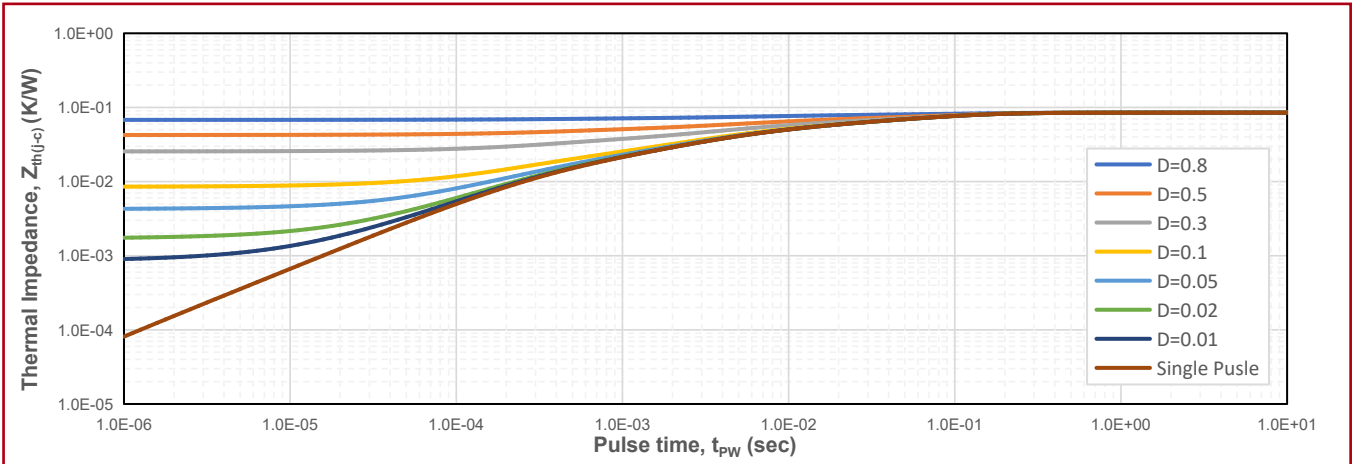
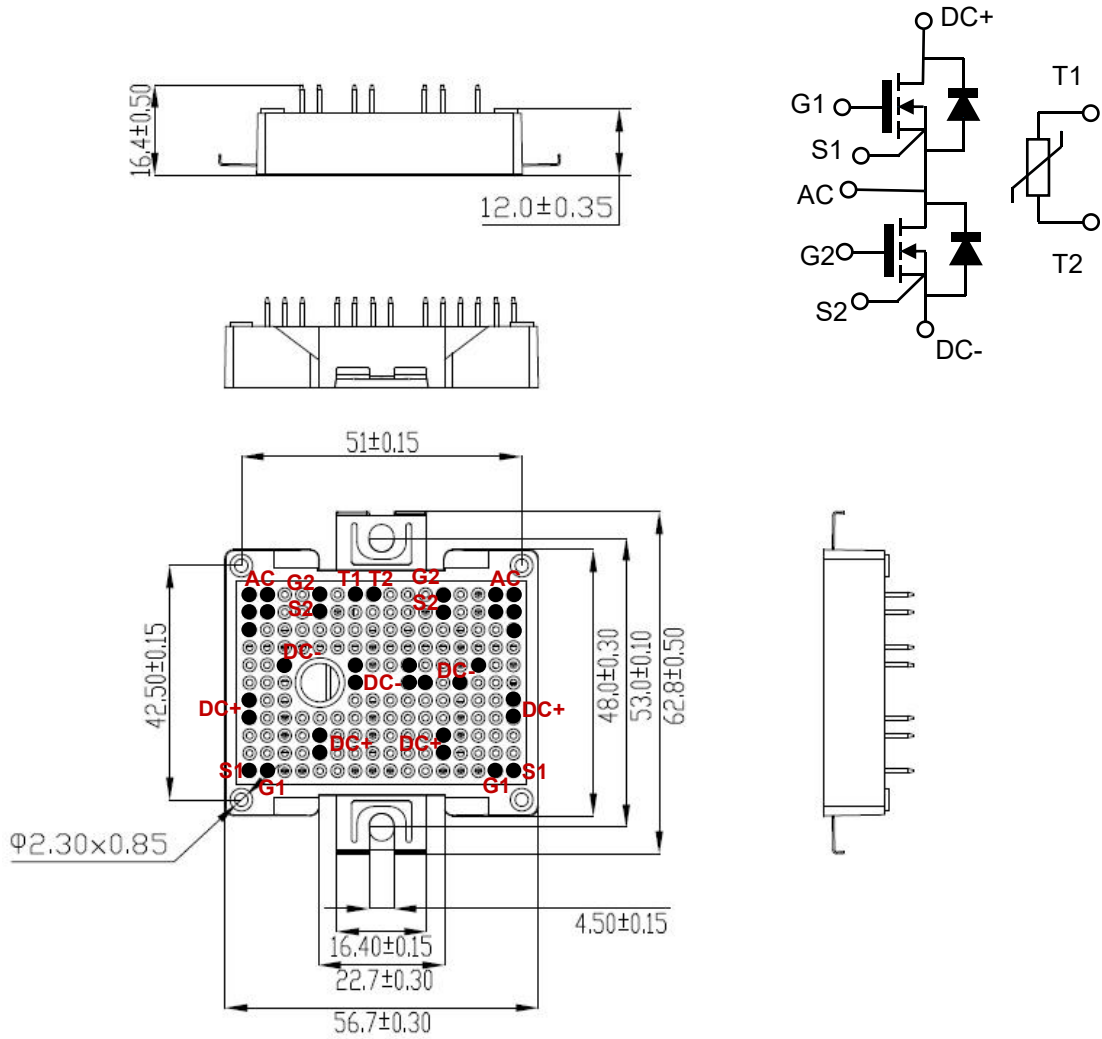


Fig.21 Transient Junction to Case Thermal Impedance

Package Dimensions



Notes

- The information provided herein is subject to change without notice.
- For other information that does not show on this datasheet, please contact us for inquiry.